

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number BAS16H-Q Part Description									
								Nexperia DHAM	Bipolar Diode		
								SMD package			
		Test Conditions	Duration	# Lots	# Quantity	# Rejects					
			TEST								
			Pre- and Post-Stress								
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below					
		JESD22-A113									
		Bake Tamb = 125 °C	24 hours								
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours								
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0					
		MIL-STD-750-1									
	HTRB	M1038 Method A									
		Tj = Tjmax, Vr = 100% of max. datasheet									
# B1	Bias	reverse voltage	1000 hours	110	4920	0					
	TC	JESD22-A104				_					
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	311	14080	0					
	UHAST	JESD22-A118									
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %									
7 A3 01	Olibiased HAST	· · · · · · · · · · · · · · · · · · ·	- 96 hours	311	14080	0					
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %									
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)									
r AJ ait	, iacocia ve	Tressare Los III a (LST) pola)									
	H3TRB	JESD22-A101									
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of									
# A2 alt		rated reverse voltage ^[1]	1000 hours	311	14080	0					
		MIL-STD-750 Method 1037	,			-					
	IOL	ton = toff, devices powered to insure ΔT_j =									
# A5	Intermittent Operating Life		1000 hours	312	14120	0					
	. 5	·									
	RSH	JESD22-A111									
# C8	Resistance to Solder Heat		10 s	269	8070	0					
	SD										
# C10	Solderability	J-STD-002		222	6660	0					

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1)
Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Small Signal Bipolar Diode	4920	0	0,86	1,16E+09

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